Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/083,469	ABE ET AL.
Examiner	Art Unit
Vieus Ma	2165

	SEARCHED				
Class	Subclass	Date	Examiner		
707	1,2,3,4 5,6,7,8 9,10, 100	5/30/2004	ΥW		
	101 102				
	103 104	J			
updated	search	2/6/2005	YW		
updated	search	8/16/2005	yan		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
inventor search (double patenting) uspto uspgpub usocr epo jpo ibmtech derwent	5/30/2004	ΥW		
acm ieee citeseer internet Search stratagy attached				
updated seach	2/6/2005	YW		
updated seach	8/16/2005			